

ABSTRACT OF THE DISCLOSURE

5 Method for testing signals of an integrated circuit

In previously known methods for testing internal signals of an integrated circuit, additional output pins were required which, in general, were linked to additional measuring pads within the integrated circuit.

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In the new method, the circuit functions are tested by using the output pins at which the output signal is present during normal operation of the integrated circuit. By means of a simple, external connection, with which a defined voltage value is set at the signal output, the integrated circuit is switched by means of an integrated control unit into a test mode in which it applies selected signals, which are to be tested, at the signal output. There is no need for additional internal measuring pads or additional output pins.

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DECEMBER 11 2001